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**** CONTINUING DATA *********** FOREIGN APPLICATIONS *******

JAPAN 2002-214476 07/23/2002

JAPAN 2003-020663 01/29/2003

JAPAN 2003-270360 07/02/2003

verified
John H.

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Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR	SHEETS	TOTAL	INDEPENDENT
35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after	COUNTRY	DRAWING	CLAIMS	CLAIMS
Verified and Acknowledged <i>John H.</i> Examiner's Signature Initials	JAPAN	15	31	8

ADDRESS

23850

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TITLE

Probe card and testing method of semiconductor chip, capacitor and manufacturing method thereof

FILING FEES	FEES: Authority has been given in Paper	<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of
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